


<b>Search Notes</b>  	<b>Application/Control No.</b>  10074996	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Christopher A Revak	<b>Art Unit</b>  2431

SEARCHED			
Class	Subclass	Date	Examiner
none	none	1/31/09	CR

SEARCH NOTES		
Search Notes	Date	Examiner
BRS Text Search: USPAT, US PGPUB, USOCR, DERWENT, IBM TDB, EPO, JPO, FPRS (see attached search strategy)	1/31/09; 7/22/09	CR
DIALOG Text Search: COMPSCI, ELECTRON, SOFTWARE (see attached search strategy)	7/22/09	CR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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